

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/587,931	STEIN ET AL.	
Examiner		Art Unit		Page 1 of 1
Michael Mapa		2617		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,708,028	03-2004	Byrne, John Daniel	455/426.1
*	B	US-2004/0235518	11-2004	Beyette et al.	455/554.2
*	C	US-7,660,292	02-2010	Wong, David	370/352
*	D	US-2004/0196810	10-2004	Kil et al.	370/331
*	E	US-2004/0221029	11-2004	Jenkins et al.	709/223
*	F	US-2003/0087629	05-2003	Juitt et al.	455/411
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.